Sea	rch	No	tes



Application/Control No.	Applicant(s)/Patent under Reexamination
10/771,636	ONODA ET AL.
Examiner	Art Unit
Tamai I E Karl	2834

	SEAR	CHED	
Class	Subclass	Date	Examiner
310	309		
359	223-226		
	290,291	1/12/2006	KIT
		_	
	·		
•			

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
			·
	L		

SEARCH N (INCLUDING SEAR)	IOTES CH STRATEGY	′)
	DATE	EXMR
•		
		<u> </u>